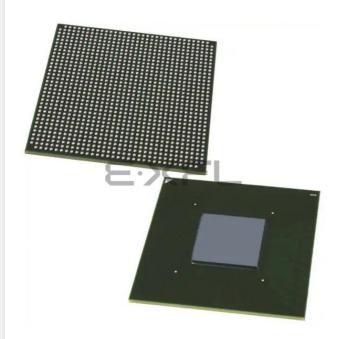
Intel - 5AGXBB1D4F35I5N Datasheet





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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	14151
Number of Logic Elements/Cells	300000
Total RAM Bits	17358848
Number of I/O	544
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA, FCBGA Exposed Pad
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxbb1d4f35i5n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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Arria V GZ Device Datasheet	
Electrical Characteristics	

Symbol	Description	Condition	Minimum ⁽¹⁾	Typical	Maximum ⁽¹⁾	Unit
		3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3.0	3.15	V
		2.5 V	2.375	2.5	2.625	V
V	I/O buffers power supply	1.8 V	1.71	1.8	1.89	V
V _{CCIO}	I/O buffers power supply	1.5 V	1.425	1.5	1.575	V
		1.35 V	1.283	1.35	1.418	V
		1.25 V	1.19	1.25	1.31	V
		1.2 V	1.14	1.2	1.26	V
V _{CCD_FPLL}	PLL digital voltage regulator power supply	_	1.425	1.5	1.575	V
V _{CCA_FPLL}	PLL analog voltage regulator power supply	_	2.375	2.5	2.625	V
VI	DC input voltage	—	-0.5		3.6	V
V _O	Output voltage	—	0		V _{CCIO}	V
	Operating junction temperature	Commercial	0		85	°C
TJ		Industrial	-40		100	°C
t (4)	Power supply ramp time	Standard POR	200 µs		100 ms	_
t _{RAMP} ⁽⁴⁾		Fast POR	200 µs		4 ms	



⁽¹⁾ The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

⁽⁴⁾ This is also applicable to HPS power supply. For HPS power supply, refer to t_{RAMP} specifications for standard POR when HPS_PORSEL = 0 and t_{RAMP} specifications for fast POR when HPS_PORSEL = 1.

Parameter Sym					V _{CCIO} (V)										
	Symbol	mbol Condition	1.2		1	1.5		1.8		2.5		.0	3.3		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold trip point	V _{TRIP}	_	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

OCT Calibration Accuracy Specifications

If you enable on-chip termination (OCT) calibration, calibration is automatically performed at power up for I/Os connected to the calibration block.

Table 1-8: OCT Calibration Accuracy Specifications for Arria V Devices

Calibration accuracy for the calibrated on-chip series termination (R_S OCT) and on-chip parallel termination (R_T OCT) are applicable at the moment of calibration. When process, voltage, and temperature (PVT) conditions change after calibration, the tolerance may change.

Symbol	Description	Condition (V)	Ca	су	Unit	
Symbol	Description		–I3, –C4	–I5, –C5	-C6	Ont
25-Ω R _S	Internal series termination with calibration (25- Ω setting)	V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	±15	±15	±15	%
50-Ω R _S	Internal series termination with calibration (50- Ω setting)	V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	±15	±15	±15	%
34- Ω and 40- Ω R_S	Internal series termination with calibration (34- Ω and 40- Ω setting)	V _{CCIO} = 1.5, 1.35, 1.25, 1.2	±15	±15	±15	%
48- Ω , 60- Ω , and 80- Ω R _S	Internal series termination with calibration (48- Ω , 60- Ω , and 80- Ω setting)	$V_{CCIO} = 1.2$	±15	±15	±15	%
50-Ω R _T	Internal parallel termination with calibration ($50-\Omega$ setting)	V _{CCIO} = 2.5, 1.8, 1.5, 1.2	-10 to +40	-10 to +40	-10 to +40	%
20- Ω , 30- Ω , 40- Ω ,60- Ω , and 120- Ω R _T	Internal parallel termination with calibration (20- Ω , 30- Ω , 40- Ω , 60- Ω , and 120- Ω setting)	V _{CCIO} = 1.5, 1.35, 1.25	-10 to +40	-10 to +40	-10 to +40	%



• Transceiver Specifications for Arria V GT and ST Devices on page 1-29 Provides the specifications for transmitter, receiver, and reference clock I/O pin.

Switching Characteristics

This section provides performance characteristics of Arria V core and periphery blocks.

Transceiver Performance Specifications

Transceiver Specifications for Arria V GX and SX Devices

Table 1-20: Reference Clock Specifications for Arria V GX and SX Devices

Symbol/Description	Condition	Trans	ceiver Speed Gr	ade 4	Transc	eiver Speed G	Unit			
Symbol/Description	Condition	Min	Тур	Max	Min	Тур	Max	Onic		
Supported I/O standards	1.2 V PCML, 1.4 V PCML, 1.5 V PCML, 2.5 V PCML, Differential LVPECL ⁽²³⁾ , HCSL, and LVDS									
Input frequency from REFCLK input pins	_	27		710	27		710	MHz		
Rise time	Measure at ±60 mV of differential signal ⁽²⁴⁾			400			400	ps		
Fall time	Measure at $\pm 60 \text{ mV}$ of differential signal ⁽²⁴⁾	_		400			400	ps		
Duty cycle		45	—	55	45	_	55	%		
Peak-to-peak differential input voltage	_	200	_	300 ⁽²⁵⁾ / 2000	200		300 ⁽²⁵⁾ / 2000	mV		



⁽²³⁾ Differential LVPECL signal levels must comply to the minimum and maximum peak-to-peak differential input voltage specified in this table.

REFCLK performance requires to meet transmitter REFCLK phase noise specification. (24)

⁽²⁵⁾ The maximum peak-to peak differential input voltage of 300 mV is allowed for DC coupled link.

1-40 Transceiver Compliance Specification

Quartus Prime 1st			Quar	tus Prime V _{OD} Se	etting			
Post Tap Pre- Emphasis Setting	10 (200 mV)	20 (400 mV)	30 (600 mV)	35 (700 mV)	40 (800 mV)	45 (900 mV)	50 (1000 mV)	Unit
16	_	_	9.56	7.73	6.49		_	dB
17	_	_	10.43	8.39	7.02		_	dB
18	_		11.23	9.03	7.52		_	dB
19	_		12.18	9.7	8.02		_	dB
20	_	_	13.17	10.34	8.59	_	_	dB
21	_	_	14.2	11.1	—	_	_	dB
22	_		15.38	11.87			_	dB
23	_	_	—	12.67	—		_	dB
24	_			13.48	_		_	dB
25	_			14.37	—		_	dB
26	_	_	_		_	_	_	dB
27	_				_		_	dB
28							_	dB
29	_				—		_	dB
30	_				_		_	dB
31							—	dB

Related Information

SPICE Models for Altera Devices

Provides the Arria V HSSI HSPICE models.

Transceiver Compliance Specification

The following table lists the physical medium attachment (PMA) specification compliance of all supported protocol for Arria V GX, GT, SX, and ST devices. For more information about the protocol parameter details and compliance specifications, contact your Altera Sales Representative.



AV-51002 2017.02.10

Symbol	Condition		-I3, -C4			-l5, -C5			-C6		- Unit
Symbol	Condition	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	SERDES factor J ≥ 8 ⁽⁷⁶⁾⁽⁷⁸⁾ , LVDS TX with RX DPA	(77)		1600	(77)		1500	(77)	_	1250	Mbps
	SERDES factor J = 1 to 2, Uses DDR Registers	(77)		(79)	(77)		(79)	(77)	_	(79)	Mbps
Emulated Differential I/ O Standards with Three External Output Resistor Network - f _{HSDR} (data rate) ⁽⁸⁰⁾	SERDES factor $J = 4$ to $10^{(81)}$	(77)		945	(77)		945	(77)		945	Mbps
Emulated Differential I/ O Standards with One External Output Resistor Network - f _{HSDR} (data rate) ⁽⁸⁰⁾	SERDES factor $J = 4$ to $10^{(81)}$	(77)		200	(77)		200	(77)		200	Mbps
t _{x Jitter} -True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps – 1.25 Gbps			160			160		_	160	ps
	Total Jitter for Data Rate < 600 Mbps			0.1	_	_	0.1	—	_	0.1	UI



 $^{^{(78)}}$ The V_{CC} and V_{CCP} must be on a separate power layer and a maximum load of 5 pF for chip-to-chip interface.

⁽⁷⁹⁾ The maximum ideal data rate is the SERDES factor (J) x the PLL maximum output frequency (f_{OUT}), provided you can close the design timing and the signal integrity simulation is clean.

⁽⁸⁰⁾ You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine the leftover timing margin.

⁽⁸¹⁾ When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Symbol	Condition		-I3, -C4			–I5, –C5		-C6			Unit
Symbol	Condition	Min	Тур	Max	Min	Тур	Мах	Min	Тур	Max	Unit
t _{x Jitter} -Emulated Differential I/O Standards with Three	Total Jitter for Data Rate 600 Mbps – 1.25 Gbps	_	-	260		_	300	_	_	350	ps
External Output Resistor Network	Total Jitter for Data Rate < 600 Mbps	—	_	0.16		_	0.18	_		0.21	UI
t _{x Jitter} -Emulated Differential I/O Standards with One External Output Resistor Network	_			0.15			0.15			0.15	UI
t _{DUTY}	TX output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	%
	True Differential I/O Standards ⁽⁸²⁾	_	_	160			180	_		200	ps
t _{RISE} and t _{FALL}	Emulated Differential I/O Standards with Three External Output Resistor Network	_		250			250			300	ps
	Emulated Differential I/O Standards with One External Output Resistor Network			500		_	500			500	ps



 $^{^{(82)}\,}$ This applies to default pre-emphasis and V_{OD} settings only.

Symbol	Parameter	Minimum	Maximum	Unit
t _{STATUS}	nSTATUS low pulse width	268	1506 ⁽⁹⁴⁾	μs
t _{CF2ST1}	nCONFIG high to nSTATUS high	_	1506 ⁽⁹⁵⁾	μs
t _{CF2CK} ⁽⁹⁶⁾	nCONFIG high to first rising edge on DCLK	1506		μs
t _{ST2CK} ⁽⁹⁶⁾	nSTATUS high to first rising edge of DCLK	2	_	μs
t _{DSU}	DATA[] setup time before rising edge on DCLK	5.5		ns
t _{DH}	DATA[] hold time after rising edge on DCLK	0		ns
t _{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	_	S
t _{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$		S
t _{CLK}	DCLK period	1/f _{MAX}		S
f _{MAX}	DCLK frequency (FPP ×8/ ×16)	_	125	MHz
t _{CD2UM}	CONF_DONE high to user mode ⁽⁹⁷⁾	175	437	μs
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	4× maximum DCLK period		
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t _{CD2CU} + (T _{init} × Clkusr period)		_
T _{init}	Number of clock cycles required for device initialization	8,576		Cycles

FPP Configuration Timing

Provides the FPP configuration timing waveforms.



⁽⁹⁴⁾ You can obtain this value if you do not delay configuration by extending the nCONFIG or the nSTATUS low pulse width.

⁽⁹⁵⁾ You can obtain this value if you do not delay configuration by externally holding the nSTATUS low.

⁽⁹⁶⁾ If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

⁽⁹⁷⁾ The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.



This document covers the electrical and switching characteristics for Arria V GZ devices. Electrical characteristics include operating conditions and power consumption. Switching characteristics include transceiver specifications, core, and periphery performance. This document also describes I/O timing, including programmable I/O element (IOE) delay and programmable output buffer delay.

Related Information

Arria V Device Overview

For information regarding the densities and packages of devices in the Arria V GZ family.

Electrical Characteristics

Operating Conditions

When you use Arria V GZ devices, they are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of Arria V GZ devices, you must consider the operating requirements described in this datasheet.

Arria V GZ devices are offered in commercial and industrial temperature grades.

Commercial devices are offered in -3 (fastest) and -4 core speed grades. Industrial devices are offered in -3L and -4 core speed grades. Arria V GZ devices are offered in -2 and -3 transceiver speed grades.

Table 2-1: Commercial and Industrial Speed Grade Offering for Arria V GZ Devices

C = Commercial temperature grade; I = Industrial temperature grade.

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Symbol	Description	Minimum	Maximum	Unit
VI	DC input voltage	-0.5	3.8	V
T _J	Operating junction temperature	-55	125	°C
T _{STG}	Storage temperature (No bias)	-65	150	°C
I _{OUT}	DC output current per pin	-25	40	mA

Table 2-3: Transceiver Power Supply Absolute Conditions for Arria V GZ Devices

Symbol	Description	Minimum	Maximum	Unit
V _{CCA_GXBL}	Transceiver channel PLL power supply (left side)	-0.5	3.75	V
V _{CCA_GXBR}	Transceiver channel PLL power supply (right side)	-0.5	3.75	V
V _{CCHIP_L}	Transceiver hard IP power supply (left side)	-0.5	1.35	V
V _{CCHSSI_L}	Transceiver PCS power supply (left side)	-0.5	1.35	V
V _{CCHSSI_R}	Transceiver PCS power supply (right side)	-0.5	1.35	V
V _{CCR_GXBL}	Receiver analog power supply (left side)	-0.5	1.35	V
V _{CCR_GXBR}	Receiver analog power supply (right side)	-0.5	1.35	V
V _{CCT_GXBL}	Transmitter analog power supply (left side)	-0.5	1.35	V
V _{CCT_GXBR}	Transmitter analog power supply (right side)	-0.5	1.35	V
V _{CCH_GXBL}	Transmitter output buffer power supply (left side)	-0.5	1.8	V
V _{CCH_GXBR}	Transmitter output buffer power supply (right side)	-0.5	1.8	V

Maximum Allowed Overshoot and Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in the following table. They may also undershoot to -2.0 V for input currents less than 100 mA and periods shorter than 20 ns.



- PowerPlay Early Power Estimator User Guide For more information about the EPE tool.
- **PowerPlay Power Analysis** ٠ For more information about PowerPlay power analysis.

Power Consumption

Altera offers two ways to estimate power consumption for a design-the Excel-based Early Power Estimator and the Quartus II PowerPlay Power Analyzer feature.

Note: You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.

Related Information

- PowerPlay Early Power Estimator User Guide For more information about the EPE tool.
- PowerPlay Power Analysis For more information about PowerPlay power analysis.

I/O Pin Leakage Current

Table 2-8: I/O Pin Leakage Current for Arria V GZ Devices

If $V_O = V_{CCIO}$ to $V_{CCIOMax}$, 100 µA of leakage current per I/O is expected.

Symbol	Description	Conditions	Min	Тур	Max	Unit
II	Input pin	$V_{I} = 0 V$ to $V_{CCIOMAX}$	-30		30	μΑ
I _{OZ}	Tri-stated I/O pin	$V_{O} = 0 V$ to $V_{CCIOMAX}$	-30	—	30	μΑ



I/O Standard	V _{CCIO} (V) ⁽¹²⁸⁾		V _{ID} (mV) ⁽¹²⁹⁾		V _{ICM(DC)} (V)		V _{OD} (V) ⁽¹³⁰⁾		0)	V _{OCM} (V) ⁽¹³⁰⁾					
	Min	Тур	Max	Min	Condition	Max	Min	Condition	Max	Min	Тур	Max	Min	Тур	Max
RSDS (HIO) (133)	2.375	2.5	2.625	100	V _{CM} = 1.25 V	_	0.3		1.4	0.1	0.2	0.6	0.5	1.2	1.4
Mini- LVDS (HIO) (134)	2.375	2.5	2.625	200	_	600	0.4	_	1.325	0.25		0.6	1	1.2	1.4
LVPECL	_		_	300			0.6	D _{MAX} ≤ 700 Mbps	1.8	_			_	_	_
(135), (136)			_	300			1	D _{MAX} > 700 Mbps	1.6	_	_		_	_	_

Glossary on page 2-73



⁽¹²⁸⁾ Differential inputs are powered by VCCPD which requires 2.5 V.

⁽¹²⁹⁾ The minimum VID value is applicable over the entire common mode range, VCM.

RL range: $90 \le RL \le 110 \Omega$. (130)

⁽¹³³⁾ For optimized RSDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.

⁽¹³⁴⁾ For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.

⁽¹³⁵⁾ LVPECL is only supported on dedicated clock input pins.

⁽¹³⁶⁾ For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.

Symbol/Description	Conditions	Trans	ceiver Spee	d Grade 2	Transc	eiver Spee	ed Grade 3	- Unit	
Symbol/Description	Conditions	Min	Тур	Мах	Min	Тур	Мах		
	$V_{CCR_GXB} = 0.85 V$ full bandwidth	_	600	_	_	600	_	mV	
V (AC and DC coupled)	$V_{CCR_{GXB}} = 0.85 V$ half bandwidth	_	600		_	600	_	mV	
$\rm V_{ICM}$ (AC and DC coupled)	$V_{CCR_{GXB}} = 1.0 V$ full bandwidth		700	_		700	_	mV	
	$V_{CCR_{GXB}} = 1.0 V$ half bandwidth		700	_		700	_	mV	
t _{LTR} ⁽¹⁴⁹⁾	—	_	_	10	_	_	10	μs	
t _{LTD} ⁽¹⁵⁰⁾	_	4			4	_		μs	
t _{LTD_manual} ⁽¹⁵¹⁾	—	4	_		4	_		μs	
t _{LTR_LTD_manual} ⁽¹⁵²⁾	_	15			15	_		μs	
Programmable equalization (AC Gain)	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)			16		_	16	dB	

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Receiver



 $^{^{(149)}}$ t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.

 $^{^{(150)}}$ t_{LTD} is time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high.

⁽¹⁵¹⁾ t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high when the CDR is functioning in the manual mode.

 $t_{\text{LTR_LTD_manual}}$ is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx_is_lockedtoref signal goes high when the CDR is functioning in the manual mode.

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
Symbol/Description	Conditions	Min	Тур	Мах	Min	Тур	Max	
Supported data range	_	600		3250/ 3125 ⁽¹⁵⁸⁾	600	_	3250/ 3125 ⁽¹⁵⁸⁾	Mbps
t _{pll_powerdown} ⁽¹⁵⁹⁾	_	1			1	_		μs
t _{pll_lock} ⁽¹⁶⁰⁾				10			10	μs

Arria V Device Overview

For more information about device ordering codes.

Clock Network Data Rate

Table 2-29: Clock Network Maximum Data Rate Transmitter Specifications

Valid data rates below the maximum specified in this table depend on the reference clock frequency and the PLL counter settings. Check the MegaWizard message during the PHY IP instantiation.

	ATX PLL			CMU PLL ⁽¹⁶¹⁾			fPLL		
Clock Network	Non-bonded Mode (Gbps)	Bonded Mode (Gbps)		Non-bonded Mode (Gbps)	Bonded Mode (Gbps)		Non-bonded Mode (Gbps)	Bonded Mode (Gbps)	Channel Span
x1 ⁽¹⁶²⁾	12.5	_	6	12.5	_	6	3.125	_	3
x6 ⁽¹⁶²⁾	_	12.5	6	_	12.5	6	_	3.125	6
x6 PLL Feedback ⁽¹⁶³⁾	_	12.5	Side-wide	_	12.5	Side-wide	_		_

⁽¹⁵⁸⁾ When you use fPLL as a TXPLL of the transceiver.



 $^{^{(159)}}$ t_{pll_powerdown} is the PLL powerdown minimum pulse width.

⁽¹⁶⁰⁾ $t_{pll \ lock}$ is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.

⁽¹⁶¹⁾ ATX PLL is recommended at 8 Gbps and above data rates for improved jitter performance.

⁽¹⁶²⁾ Channel span is within a transceiver bank.

⁽¹⁶³⁾ Side-wide channel bonding is allowed up to the maximum supported by the PHY IP.

t_{ARESET}

Symbol	Parameter	Min	Тур	Max	Unit
f _{OUT} ⁽¹⁶⁹⁾	Output frequency for an internal global or regional clock (C3, I3L speed grade)	—	—	650	MHz
IOUT	Output frequency for an internal global or regional clock (C4, I4 speed grade)	—		580	MHz
f _{OUT_EXT} ⁽¹⁶⁹⁾	Output frequency for an external clock output (C3, I3L speed grade)	—	_	667	MHz
IOUT_EXT	Output frequency for an external clock output (C4, I4 speed grade)	_	_	533	MHz
toutduty	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
t _{FCOMP}	External feedback clock compensation time	_		10	ns
f _{dyconfigclk}	Dynamic configuration clock for mgmt_clk and scanclk		_	100	MHz
t _{LOCK}	Time required to lock from the end-of-device configuration or deassertion of areset	_	_	1	ms
t _{DLOCK}	DLOCK Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/ delays)		_	1	ms
	PLL closed-loop low bandwidth	_	0.3		MHz
f_{CLBW}	PLL closed-loop medium bandwidth	_	1.5		MHz
	PLL closed-loop high bandwidth (170)	_	4		MHz
t _{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps

10

_

Minimum pulse width on the areset signal





ns

 $^{^{(169)}}$ This specification is limited by the lower of the two: I/O f_{MAX} or f_{OUT} of the PLL.

⁽¹⁷⁰⁾ High bandwidth PLL settings are not supported in external feedback mode.

2-44 Periphery Performance

Description	Min	Тур	Max	Unit
Diode ideality factor	1.006	1.008	1.010	—

Periphery Performance

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

Note: The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

High-Speed Clock Specifications

Table 2-39: High-Speed Clock Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

For LVDS applications, you must use the PLLs in integer PLL mode.

Arria V GZ devices support the following output standards using true LVDS output buffer types on all I/O banks.

- True RSDS output standard with data rates of up to 230 Mbps
- True mini-LVDS output standard with data rates of up to 340 Mbps



Number of DQS Delay Buffers	C3, I3L	C4, I4	Unit
4	120	128	ps

Memory Output Clock Jitter Specifications

Table 2-50: Memory Output Clock Jitter Specification for Arria V GZ Devices

The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.

The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.

The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

Clock Network	Parameter	Symbol -	С3,	I3L	C4	Unit	
CIOCK NELWOIK	ralameter		Min	Мах	Min	Мах	Onic
	Clock period jitter	t _{JIT(per)}	-55	55	-55	55	ps
Regional	Cycle-to-cycle period jitter	t _{JIT(cc)}	-110	110	-110	110	ps
	Duty cycle jitter	t _{JIT(duty)}	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	t _{JIT(per)}	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	t _{JIT(cc)}	-165	165	-165	165	ps
	Duty cycle jitter	t _{JIT(duty)}	-90	90	-90	90	ps
	Clock period jitter	t _{JIT(per)}	-30	30	-35	35	ps
PHY Clock	Cycle-to-cycle period jitter	t _{JIT(cc)}	-60	60	-70	70	ps
	Duty cycle jitter	t _{JIT(duty)}	-45	45	-56	56	ps



2-64 FPP Configuration Timing when DCLK to DATA[] > 1

Symbol	Parameter	Minimum	Maximum	Unit
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times \text{maximum DCLK}$ period	—	—
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (8576 × CLKUSR period) (215)	—	—

Related Information

- DCLK-to-DATA[] Ratio (r) for FPP Configuration on page 2-57
- Configuration, Design Security, and Remote System Upgrades in Arria V Devices





⁽²¹⁵⁾ To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section of the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.

Symbol	Parameter	Minimum	Maximum	Unit
t _{CO}	DCLK falling edge to AS_DATA0/ASDO output		4	ns
t _{SU}	Data setup time before falling edge on DCLK	1.5	—	ns
t _H	Data hold time after falling edge on DCLK	0	—	ns
t _{CD2UM}	CONF_DONE high to user mode (216)	175	437	μs
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times \text{maximum DCLK}$ period	_	_
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t _{CD2CU} + (8576 × Clkusr period)	_	_

Table 2-59: DCLK Frequency Specification in the AS Configuration Scheme

This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

The AS multi-device configuration scheme does not support ${\tt DCLK}$ frequency of 100 MHz.

Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

Related Information

- Passive Serial Configuration Timing on page 2-67
- Configuration, Design Security, and Remote System Upgrades in Arria V Devices





⁽²¹⁶⁾ To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the "Initialization" section of the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.

Glossary

Table 2-68: Glossary

